

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

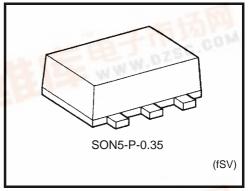
# TC7SH08FS

#### 2-INPUT AND GATE

#### **Features**

High speed:  $t_{pd} = 4.3$  ns (typ.) at  $V_{CC} = 5$  V Low power dissipation:  $I_{CC} = 2$   $\mu$ A (max) at Ta = 25°C High noise immunity:  $V_{NIH} = V_{NIL} = 28\%$  V<sub>CC</sub> (min) 5.5V tolerant input.

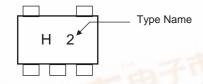
Wide operating voltage range:  $V_{CC}$  (opr) = 2~5.5 V

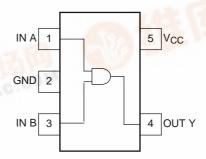


# Marking (top view)

### Pin Assignment









## **Maximum Ratings (Ta = 25°C)**

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	-0.5~7.0	V
DC input voltage	V <sub>IN</sub>	-0.5~7.0	V
DC output voltage	V <sub>OUT</sub>	−0.5~V <sub>CC</sub> + 0.5	٧
Input diode current	I <sub>IK</sub>	-20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V <sub>CC</sub> /ground current	Icc	±50	mA
Power dissipation	PD	50	mW
Storage temperature	T <sub>stg</sub>	-65~150	°C

## **Logic Diagram**



### **Truth Table**

Α	В	Υ
L	L	L
L	Н	L
Н	L	L
Н	Н	Н

# **Recommended Operating Conditions**

Characteristics	Symbol	Rating	Unit	
Supply voltage	V <sub>CC</sub>	2.0~5.5	V	
Input voltage	V <sub>IN</sub>	0~5.5	V	
Output voltage	V <sub>OUT</sub>	0~Vcc	V	
Operating temperature	T <sub>opr</sub>	-40~85	°C	
Input rise and fall time	dt/dv	0~100 (V <sub>CC</sub> = 3.3 ± 0.3 V)	ns/V	
input rise and rail time	αί/αν	$0 \sim 20 \; (V_{CC} = 5 \pm 0.5 \; V)$	115/ V	

## **Electrical Characteristics**

#### **DC Characteristics**

	Test					Ta = 25°C			Ta = -40~85°C		
Characteristics Symbol Circui		Circuit	Test Condition		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Unit
High-level input					1.50	_	_	1.50	_		
voltage	V <sub>IH</sub> —		_		3.0~ 5.5	V <sub>CC</sub> × 0.7		_	V <sub>CC</sub> × 0.7	_	V
Low-level input					2.0	_		0.50	_	0.50	V
voltage	V <sub>IL</sub>	_		_		_		V <sub>CC</sub> × 0.3	_	V <sub>CC</sub> × 0.3	
			V <sub>IN</sub> = V <sub>IH</sub>	Ι <sub>ΟΗ</sub> = -50 μΑ	2.0	1.9	2.0	_	1.9	_	V
High-level VOH					3.0	2.9	3.0	_	2.9	_	
	V <sub>OH</sub>				4.5	4.4	4.5	_	4.4	_	
				I <sub>OH</sub> = -4 mA	3.0	2.58		_	2.48	_	
				$I_{OH} = -8 \text{ mA}$	4.5	3.94		_	3.80	_	
					2.0	_	0.0	0.1	_	0.1	
Low-level output voltage		V <sub>IN</sub> = V <sub>IH</sub>	I <sub>OL</sub> = 50 μA	3.0	_	0.0	0.1	_	0.1	V	
	_			4.5	_	0.0	0.1	_	0.1		
			0. 1.2	I <sub>OL</sub> = 4 mA	3.0	_	_	0.36		0.44	
				I <sub>OL</sub> = 8 mA	4.5	_		0.36	_	0.44	
Input leakage current	I <sub>IN</sub>	_	V <sub>IN</sub> = 5.5 V or GND		0~ 5.5	_		±0.1	_	±1.0	μА
Quiescent supply current	Icc	_	V <sub>IN</sub> = V <sub>CC</sub> or GND			_	_	2.0	_	20.0	μА

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## AC Characteristics (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics Sy	Cumbal	Test Circuit	Т	est Conditio	st Condition		Ta = 25°C			Ta = -40~85°C	
	Symbol			V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Тур.	Max	Min	Max	Unit
Propagation delay time	t <sub>P</sub> LH t <sub>P</sub> HL	_	_	3.3 ± 0.3	15		6.2	8.8	1.0	10.5	ns ns
					50		8.7	12.3	1.0	14.0	
				5.0 ± 0.5	15	_	4.3	5.9	1.0	7.0	
					50	_	5.8	7.9	1.0	9.0	
Input capacitance	C <sub>IN</sub>	_		_		_	4	10	_	10	pF
Power dissipation capacitance	C <sub>PD</sub>	_			(Note)		14	_	_	_	pF

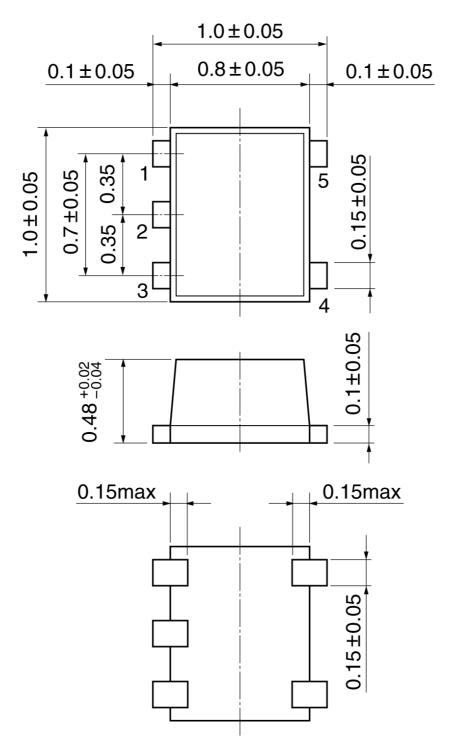
Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

## **Package Dimensions**

SON5-P-0.35 Unit:mm



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Weight:0.001g(typ.)

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